Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination OHNISHI ET AL.		
10/529,145			
Examiner	Art Unit		
Yonel Beaulieu/	3661		

/Yonel Beaulieu/

SEARCHED					
Class	Subclass	Date	Examiner		
701	117-119	5/12/2008	YB		
	200				
	213-215				
340	988				
701	209				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examine	
Int. S	Search	5/12/2008	YB	

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DATE	EXMR
5/12/2008	YB
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